

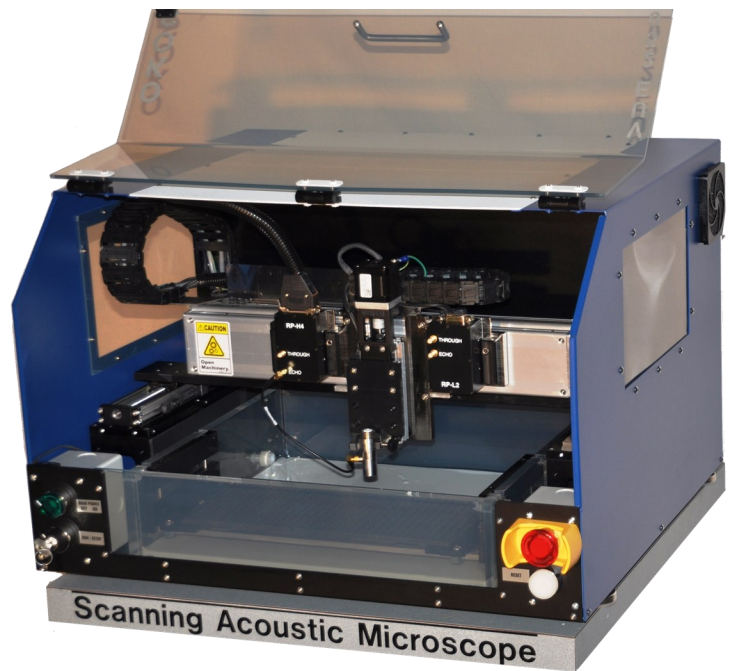
# OKOS

# VUE 250

OKOS scanning acoustic microscopes are designed with advanced instrumentation and software to increase productivity and aid in improving the manufacturing process.

All-in-one software for F/A labs and Fabrication environments include:

- ODIS Basic (user friendly)
- ODIS Advanced (detailed analysis)
- ODIS Production (streamlined scanning)
- ODIS Offline Analysis (virtual scanning)



*Semiconductor Package Failure Analysis*

## FEATURES

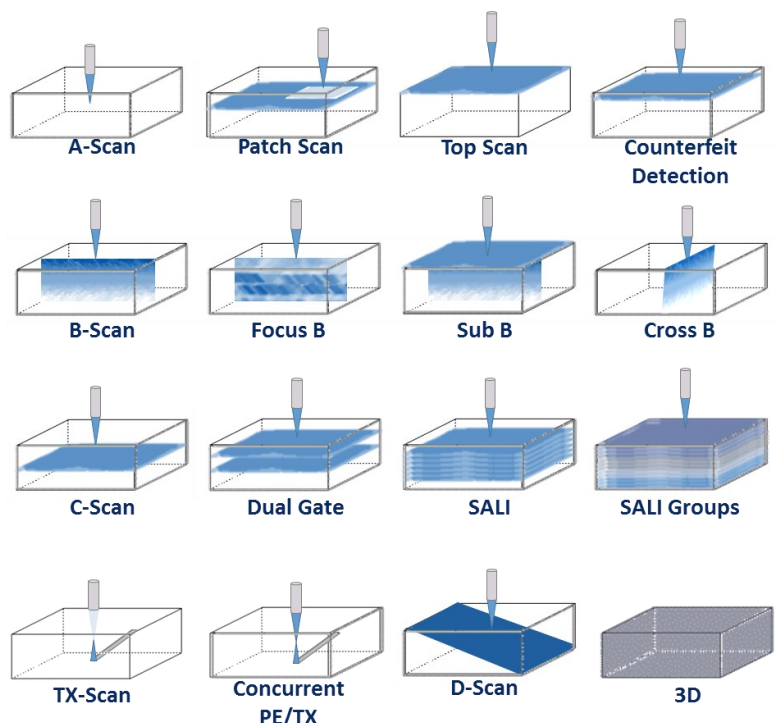
OKOS VUE 250 imaging power includes thickness measurement and discontinuity detection. Optional Enhanced Flip Chip Imaging package boosts non-destructive analysis capabilities of more traditional plastic packages.

- Optional Pulse Echo/ Through Transmission
- Pass/Fail scan sorting
- Reduced footprint and ergonomic design
- High speed/Low noise scanning

OKOS transducers range from 2 MHz to Ultra High Frequencies. Additional advancements in traditional and hybrid package specific transducers improve image quality and defect resolution.

Counterfeit Detection  
Product Reliability  
Process Validation  
Vendor Qualification

Product Inspection  
Quality Control  
Failure Analysis  
R&D



# SPECS

**Maintenance Free Scan Axis**  
Motor: Linear Servo  
Max Velocity: 500 mm/s  
Accuracy & Repeatability: +/- 5 micron  
Scan Envelope: 250 mm

**Low Maintenance Step Axis**  
Step Envelope: 150 mm

**Low Maintenance Focus Axis**  
Focus Envelope: 30 mm

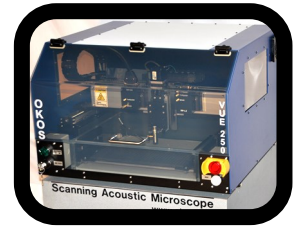
**Dimensions**  
L 635 mm x W 559 mm x H 407 mm  
52 kg

**Customer Interface**  
Dual 22" HD LED Monitors

**Fixtures**  
Tray Fixture  
*Optional Through Transmission Bracket*  
LED illumination

**Instrumentation**  
Single or Dual Channel Digital Pulser/Receiver  
1 GHz Digitizer

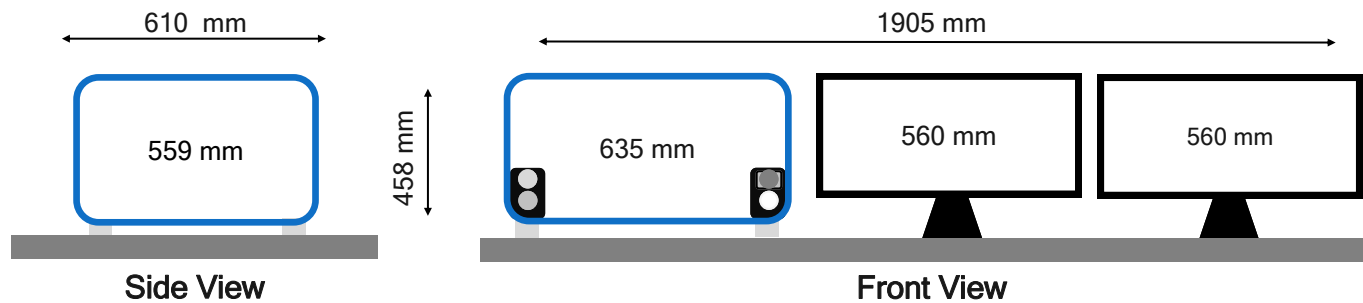
Custom transducers to fit your F/A needs



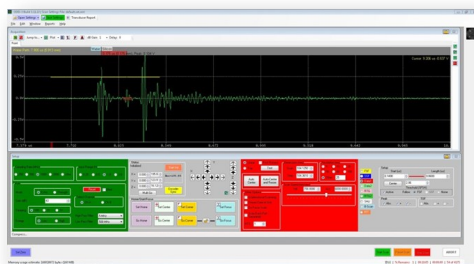
# WORKSPACE

*Table Top Ready Scanner*

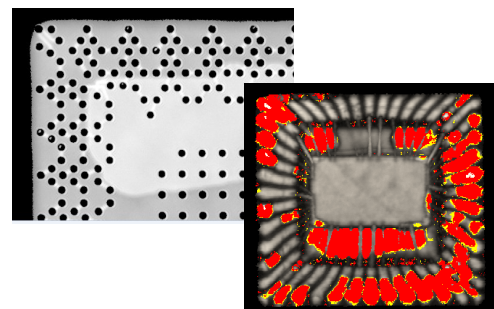
*\*table must be sturdy enough to hold 170lbs and resist vibration*



# OKOS Digital Imaging System (ODIS)



ODIS is the latest Acoustic Microscopy software with rich technical content built on current platforms and industry feedback. It includes both time domain and frequency domain imaging in real-time. Advanced analysis is provided through quantitative tools for measurement and classification of parts. The Analysis version of ODIS allows non-scanning computers to virtually scan, view, and analyze data for simultaneous real-time analysis or post collection review. Previously undetected flaws can now be imaged with poled peak analysis. Supplied with your choice of Windows 7 or 8.



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